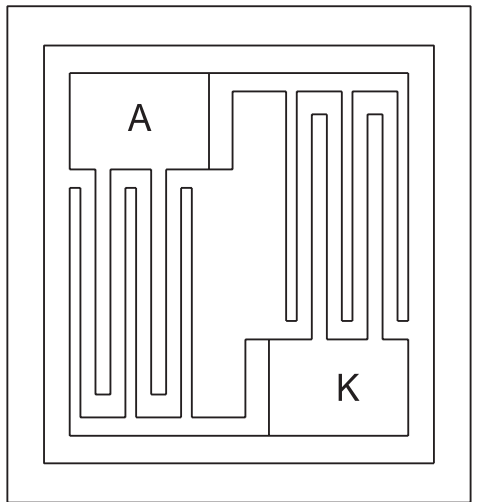


**PROCESS DETAILS**

Process	PLANAR PASSIVATED
Die Size	27.5 x 27.5 MILS
Die Thickness	11 MILS
Anode Bonding Pad Area	7.1 x 5.1 MILS
Cathode Bonding Pad Area	7.1 x 5.1 MILS
Top Side Metalization	Al - 30,000Å
Back Side Metalization	Au - 13,000Å

**GEOMETRY**



BACKSIDE GATE R1

**GROSS DIE PER 4 INCH WAFER**

14,930

**PRINCIPAL DEVICE TYPES**

2N6028

The Typical Electrical Characteristics data for this chip is currently being revised.

For the latest updated data for this Chip Process, please visit our website at:

[www.centrasemi.com/chip](http://www.centrasemi.com/chip)

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R1 (1-August 2002)